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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10029390	FILING DATE 12/28/2001	CLASS 324.133	SUBCLASS 18	GAU 2858	EXAMINER PERT
<b>**APPLICANTS:</b> Kim Ki; You Young; Lee Keun; Park Sung;					
<b>**CONTINUING DATA VERIFIED:</b>					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> REPUBLIC OF KOREA 2001-73419 11/23/2001					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO 054216-5024	
TITLE : Test pattern for measuring contact resistance and method of manufacturing the same <small>U.S. DEPT. OF COMM./PAT. &amp; TM.-PTO-435L (Rev. 12-94)</small>					

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>				
		Assistant Examiner	<table border="1"><tr><td>Total Claims</td><td>Print Claim for O.G.</td></tr></table>	Total Claims	Print Claim for O.G.	
Total Claims	Print Claim for O.G.					
<b>ISSUE FEE</b>		<b>DRAWING</b>				
Amount Due	Date Paid	Primary Examiner	<table border="1"><tr><td>Sheets Drwg.</td><td>Figs. Drwg.</td><td>Print Fig.</td></tr></table>	Sheets Drwg.	Figs. Drwg.	Print Fig.
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<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		<b>PREPARED FOR ISSUE</b>	Application Examiner			
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